

Material technology enhances the density and the productivity of the package

May 31, 2018

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Packaging Solution Center

Advanced Performance Materials Business Headquarter

 **Hitachi Chemical Co., Ltd.**

Outline

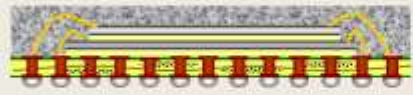
- 1. Materials for high density packaging**
- 2. Bonding Force Leveling (BFL) Film**
- 3. Molded reflow process with NCF & EMC**
- 4. Bump Stabbing process**
- 5. RDL-first FO-PLP TV and “JOINT”**
- 6. Summary**

Packaging material product line up of Hitachi Chemical

Flip Chip BGA



Stacked CSP



Wafer Level CSP



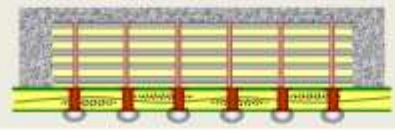
FOWLP



2.5D PKG



3D PKG



- Buffer Coatings/Redistribution Materials
- CMP Slurry
- Die Attach Film
- Dielectric Material/Build UP, SAP Prepreg
- Dry Film Resist
- Release Film
- Substrate
- Solder Resist
- Temporary Bonding Film
- Solid/Liquid EMC, Embedded Sheet
- Thermally Conductive Film
- Temporary Bonding Film
- Underfill

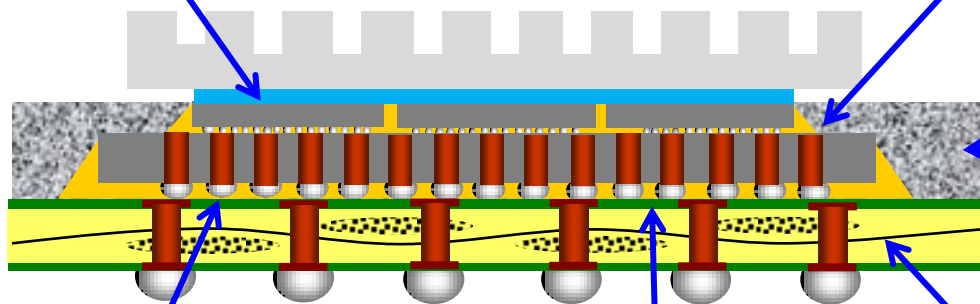
Material can contribute to the performance of the high density package

Thermal Interface material

- High thermal conductive : 40 W/mK

Underfill material

- CUF : Small gap filling: 25 μm
- NCF : Thin die: <50 μm



EMC

- Thermal conductive: 6 W/mK
- Low loss: Df=0.005 @60GHz

Organic laminate

- Low CTE: 0.8 ppm/°C
- Low Loss: Df=0.0035 @10GHz

Solder resist

- High Tg: >200°C
- Low CTE: <20 ppm/°C

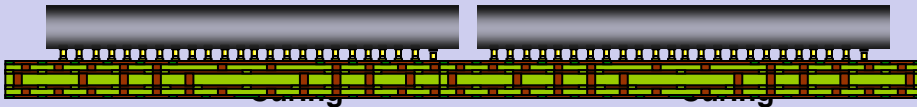
Dry film resist

- Resolution: L/S=2/2 μm

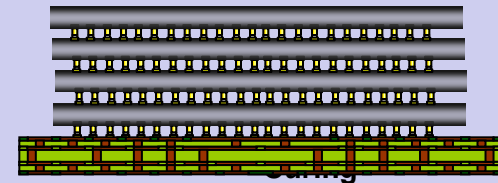
Can material do other contributions?

Typical die configurations of high density packages

Side by side (2.5D)



Die stack with TSV (3D)



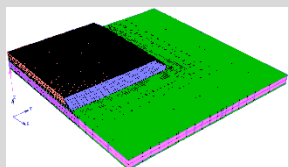
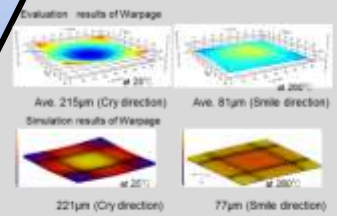
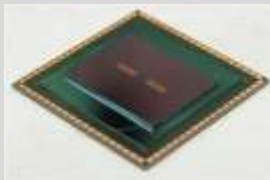
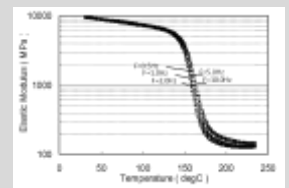
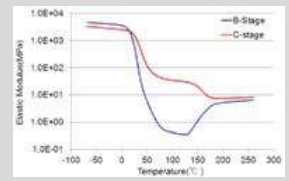
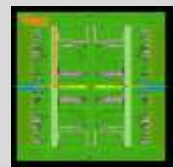
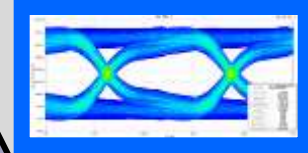
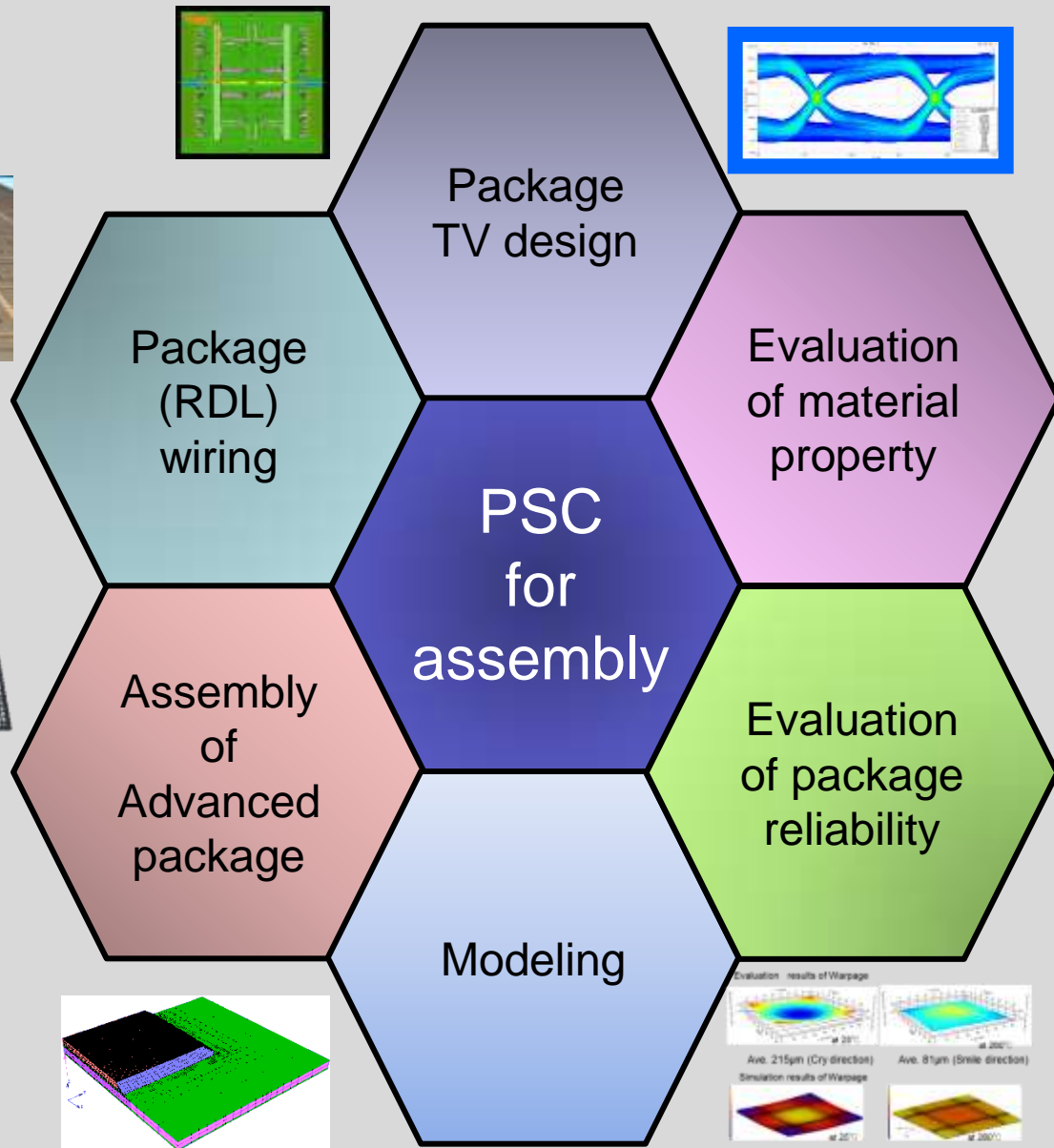
- Fine pitch
- Many bumps

Precise alignment and small bump interconnection.
Thermal compression bonding (TCB) is usually used.

Low productivity!

Can material enhance the productivity?

Function of Packaging Solution Center (PSC) of HC

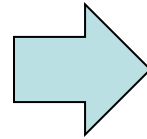
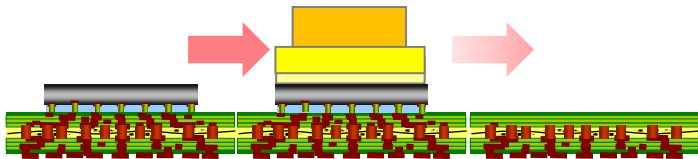


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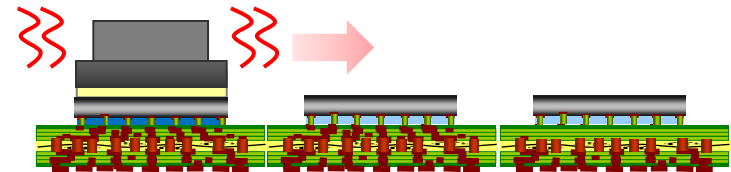
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◆ Conventional TCB process

Pre-bonding



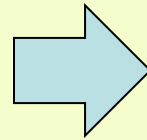
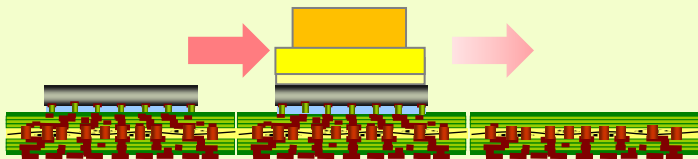
Main bonding (die by die)



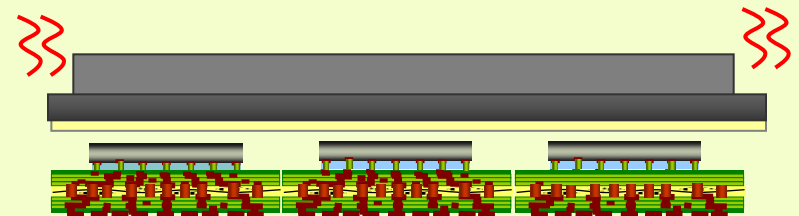
- The die by die sequential process step

◆ Gang-bonding process

Pre-bonding

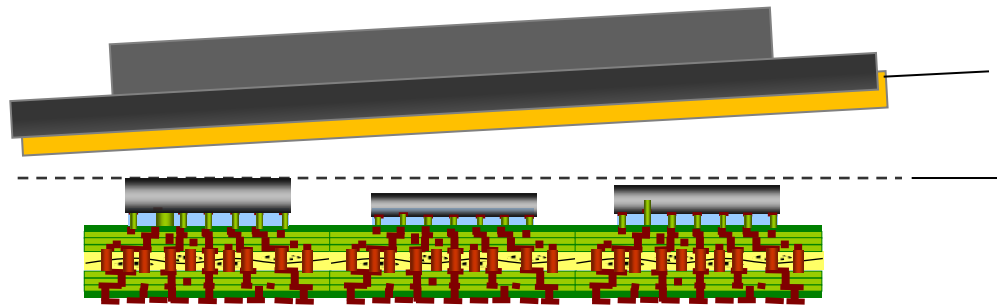


Main bonding (gang-bonding)

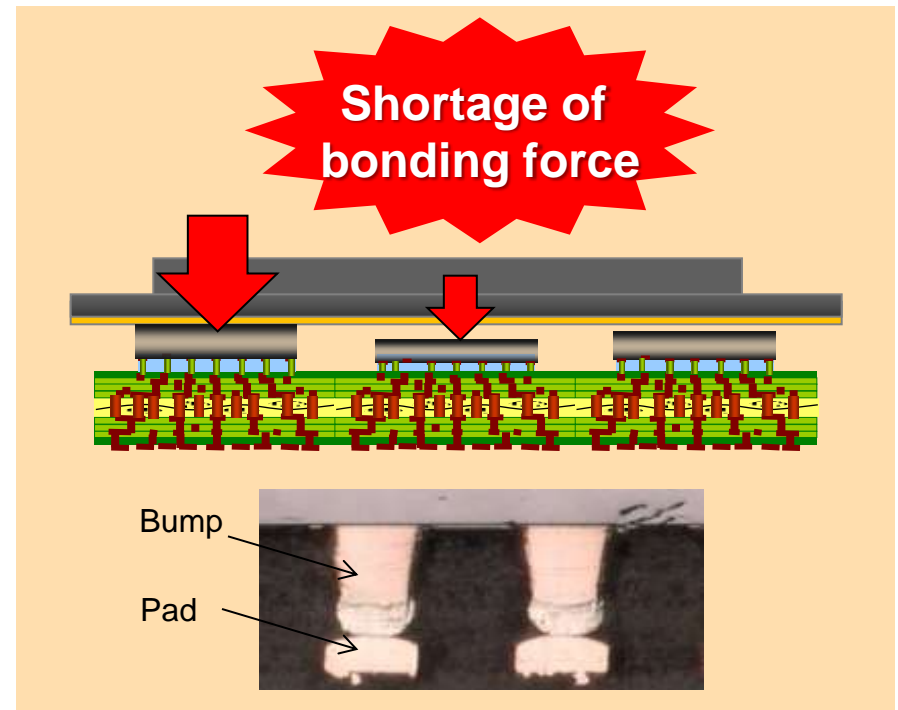
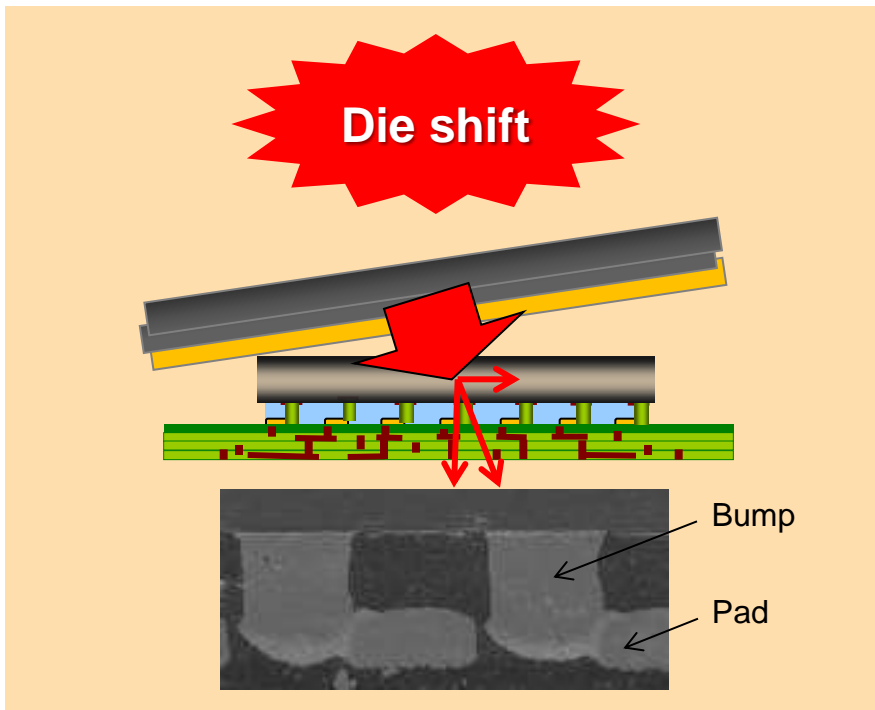


- Multi die soldering on the substrate with single large head

Gang-bonding process can significantly enhance the productivity



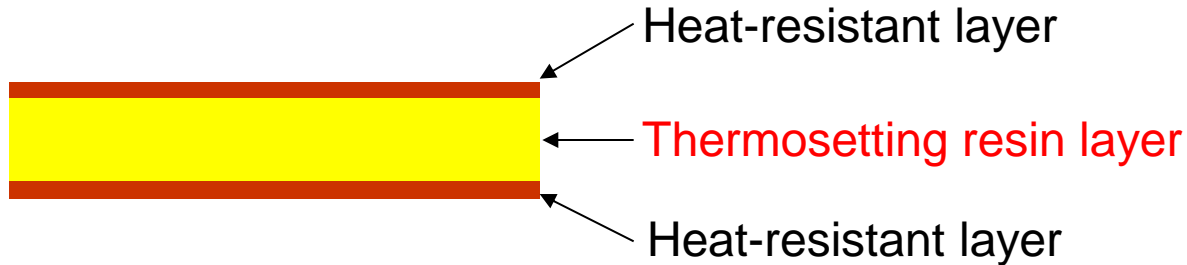
- Unparalleled head
- Unevenness of the die height (due to bump height, pad thickness, and thickness unevenness of substrate surface)



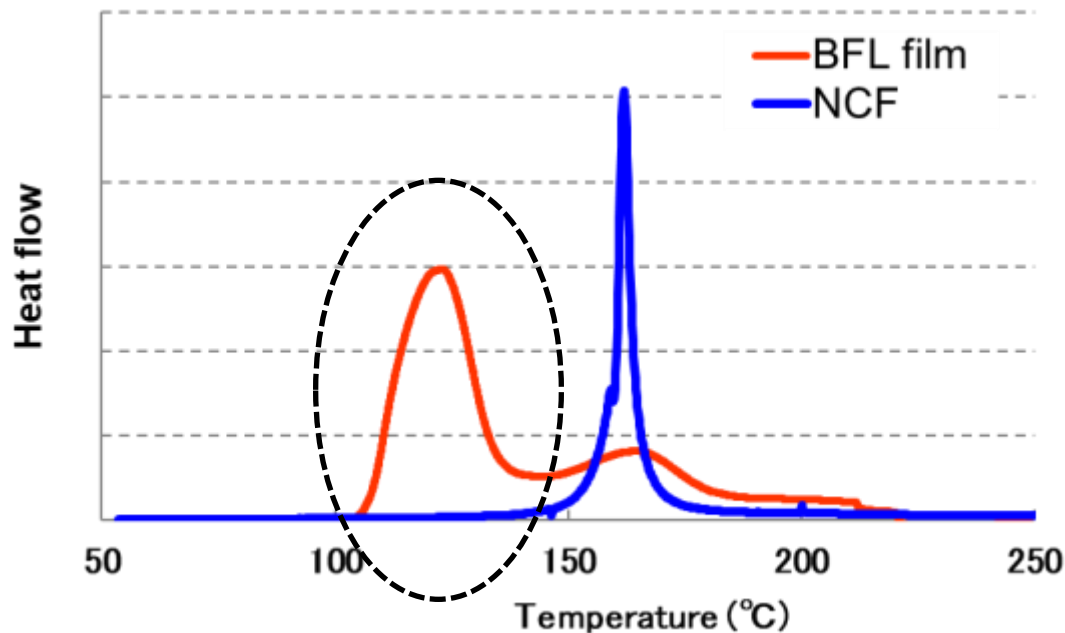
Die shift and the shortage of bonding force may happen at the gang-bonding

BFL: Bonding Force Leveling

◆ Structure of the BFL film



◆ DSC chart of the BFL film

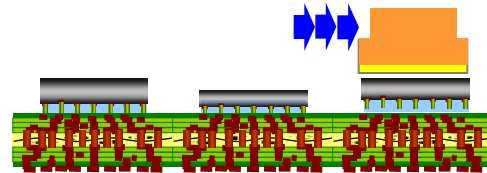


✓ Thermosetting resin layer of BFL film cures faster than the resin of NCF to compensate the height difference among the dies before multi dies gang bonding.

BFL film compensates the deviation

BFL can enhance the productivity of TCB process

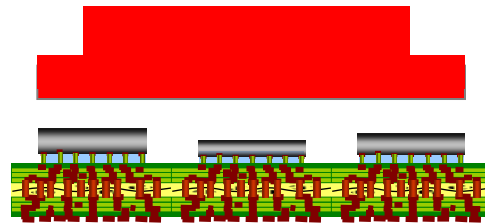
Die placement



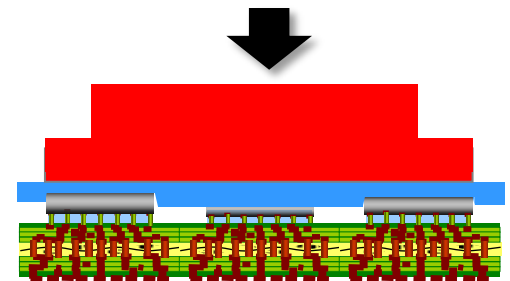
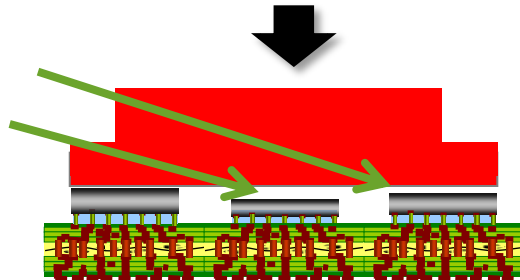
Without BFL film

With BFL film

Gang bonding



Interconnection error due to gap deviation

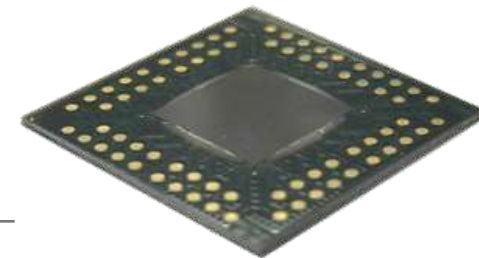


BFL can compensate the gap deviation
High productivity gang bonding !

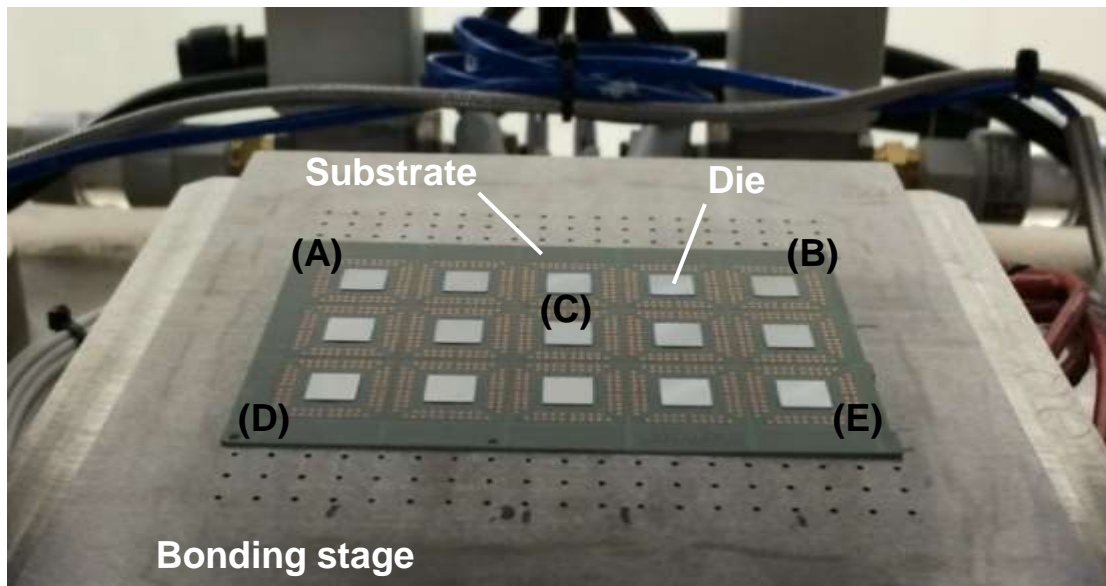
Set up of the test of CoS gang-bonding with BFL

◆ Test vehicle specification

Die	7.3 mm × 7.3 mm, 100 μm ^t Peripheral bump : 80 μm pitch Full array bump : 300 μm pitch Bump height : Cu Pillar (30 μm ^t) + SnAg Solder (15 μm ^t)
Substrate	Top layer Cu thickness: 15 μm Total thickness: 0.36 mm
NCF	Thickness: 40 μm



TV appearance



- Condition: 80 °C/50 N/3 s
- Gang bonding by HTB-MM (Alpha Design Co., Ltd.)
Condition: 300 °C/750 N/15 s

◆ Evaluation

- Daisy chain (all dies)
- Die shift (A-E dies)
- Void in NCF

The results of gang-bonding with BFL

Item	No film	Teflon	BFL film
Daisy chain test (Pass /Total)	8/15	14/15	15/15
Die shift after pre-bonding			
Ave. die shift	30 μm	27 μm	5 μm
Void in NCF by C-SAM observation			
	NG	OK	OK

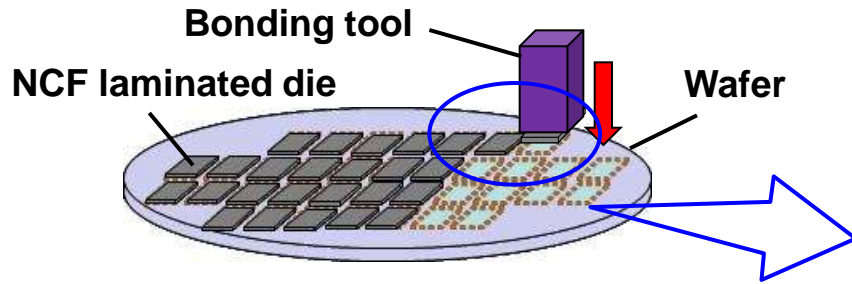
The BFL film performed worked well at 15-die gang bonding

Contents

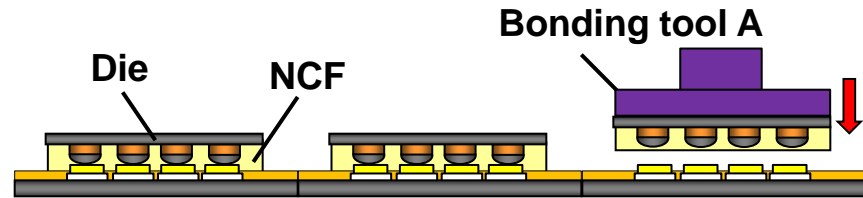
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“Molded reflow” process

Pre-bonding



Only placement!
No TCB!



Molding



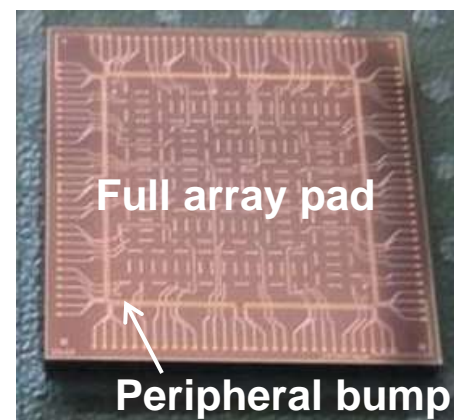
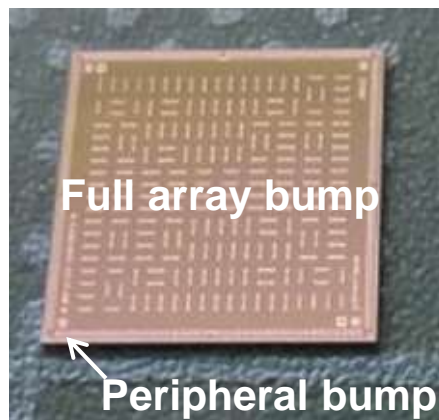
Reflow



Solder joint formation



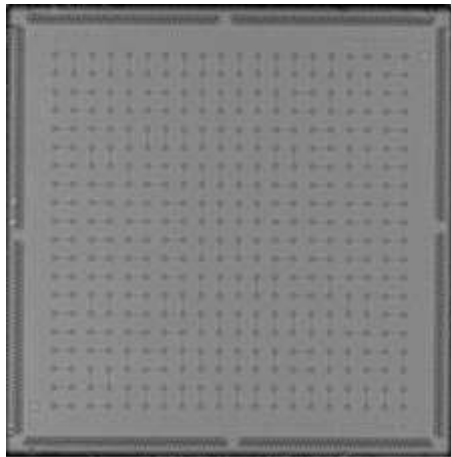
Top die	7.3 mm x 7.3 mm, 100 μm^t Passivation : SiN Peripheral bump : 80 μm pitch, 648 pin Full array bump : 300 μm pitch, 400 pin Bump height : Cu Pillar (30 μm^t) + Sn/Ag Solder (15 μm^t)
Bottom die	10 mm \times 10 mm, 100 μm^t Passivation : SiN Pad : Ni/Au plating



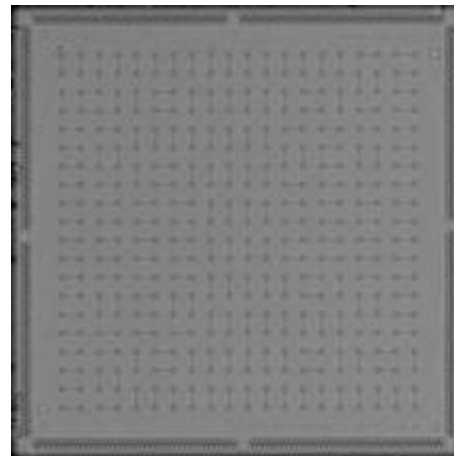
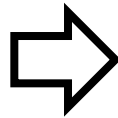
NCF: Specially designed for reflow process (Lower viscosity NCF).

Pre-bonding condition: 130 ° C / 2 s

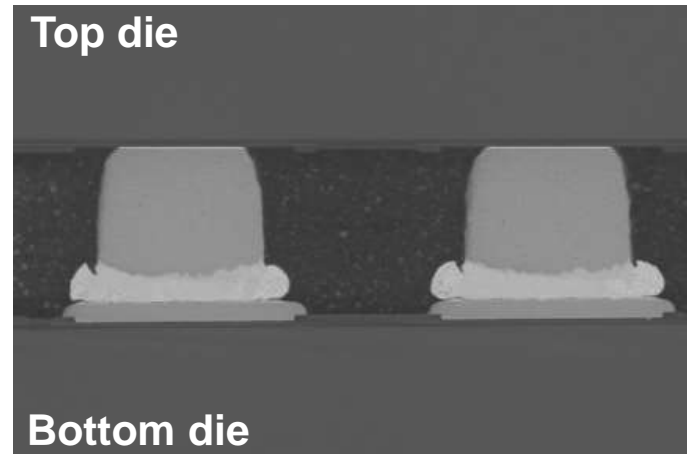
**Reflow condition: 170 ° C / 2 min + 190 ° C / 2 min + 260 ° C / 2 min
+ 190 ° C / 2 min by convection ovens.**



**SAM image
After pre-bonding**



**SAM image
After reflow**

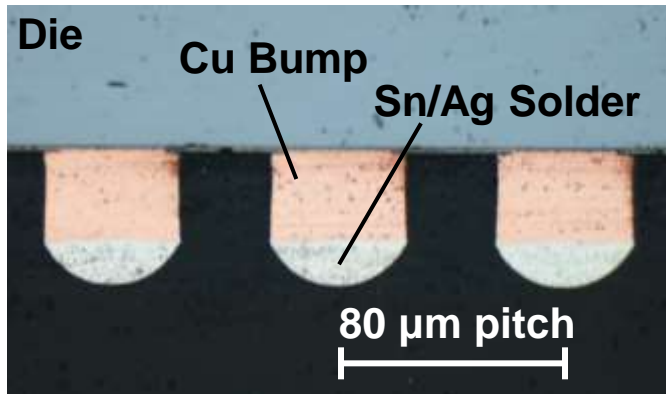


SEM image of cross section

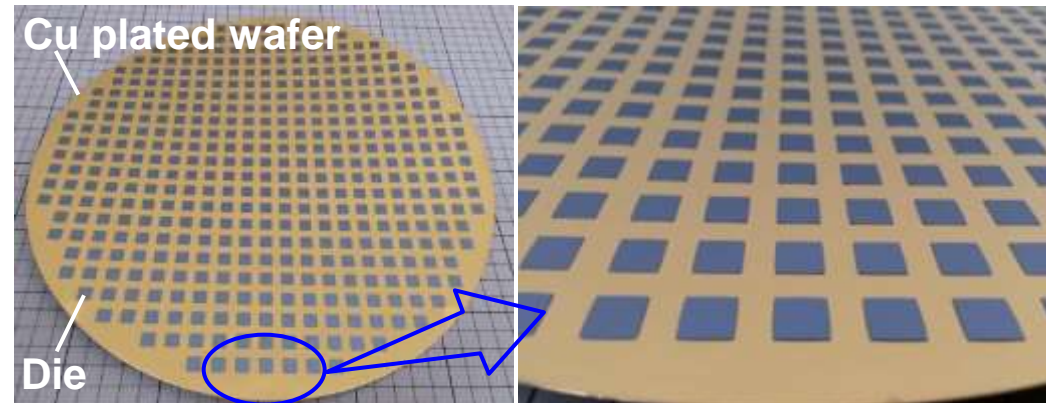
Void Suppression and making solder joint were successfully archived with the NCF by molded reflow process.

CoW assembly by molded reflow

Top die	Size : 7.3 mm × 7.3 mm , Thickness 100 μm Peripheral bump : 80 μm pitch, 328 pin Bump height : Cu Pillar (30 μm) + Sn/Ag Solder (15 μm)
Plated wafer	12 inch wafer , Thickness 250 μm Plating thickness : Cu 4 μm/ Ni 4 μm /Au 0.1 μm



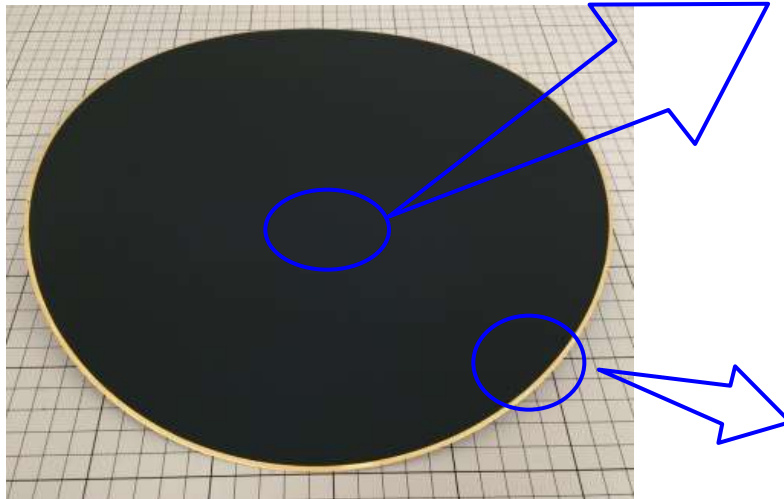
Bump structure of top die



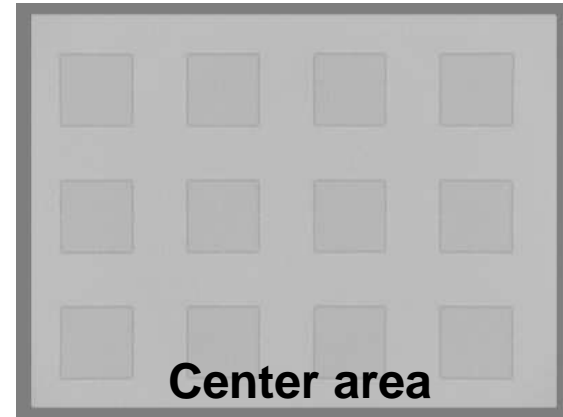
Photos of CoW

X-ray image of molded reflow CoW

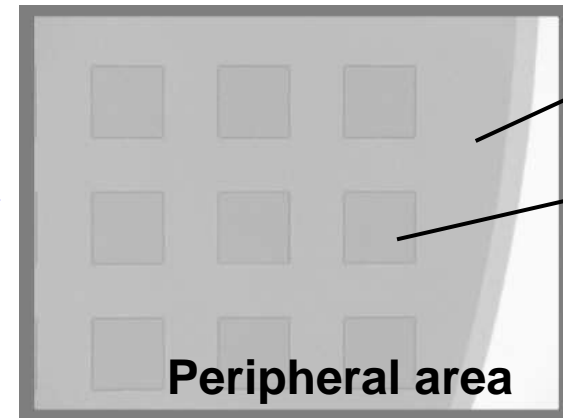
Chip on wafer: 421 dies
Gap between dies: 5 mm
Molding cap thickness: 300 μm



After molding
(Before reflow treatment)



Center area



Plated wafer

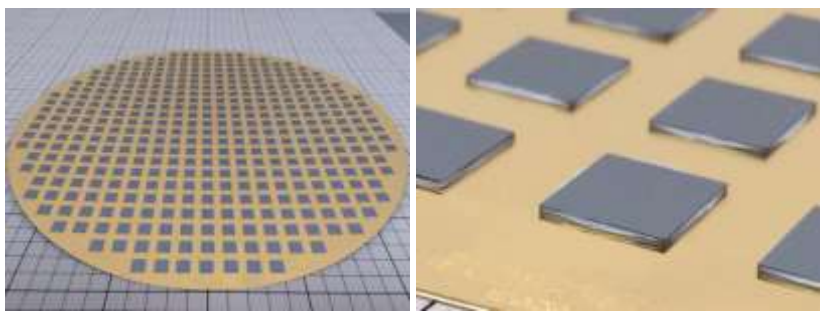
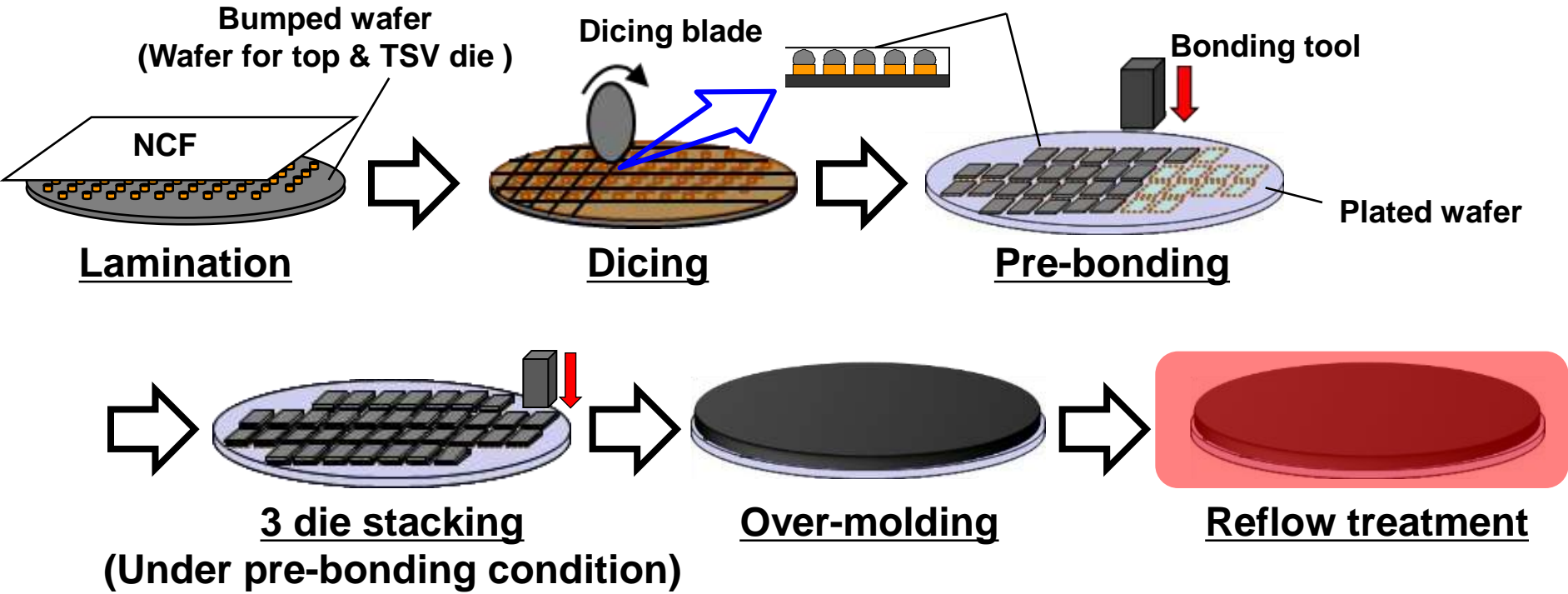
Die

Peripheral area

X-ray image after molding

No die shift was observed.

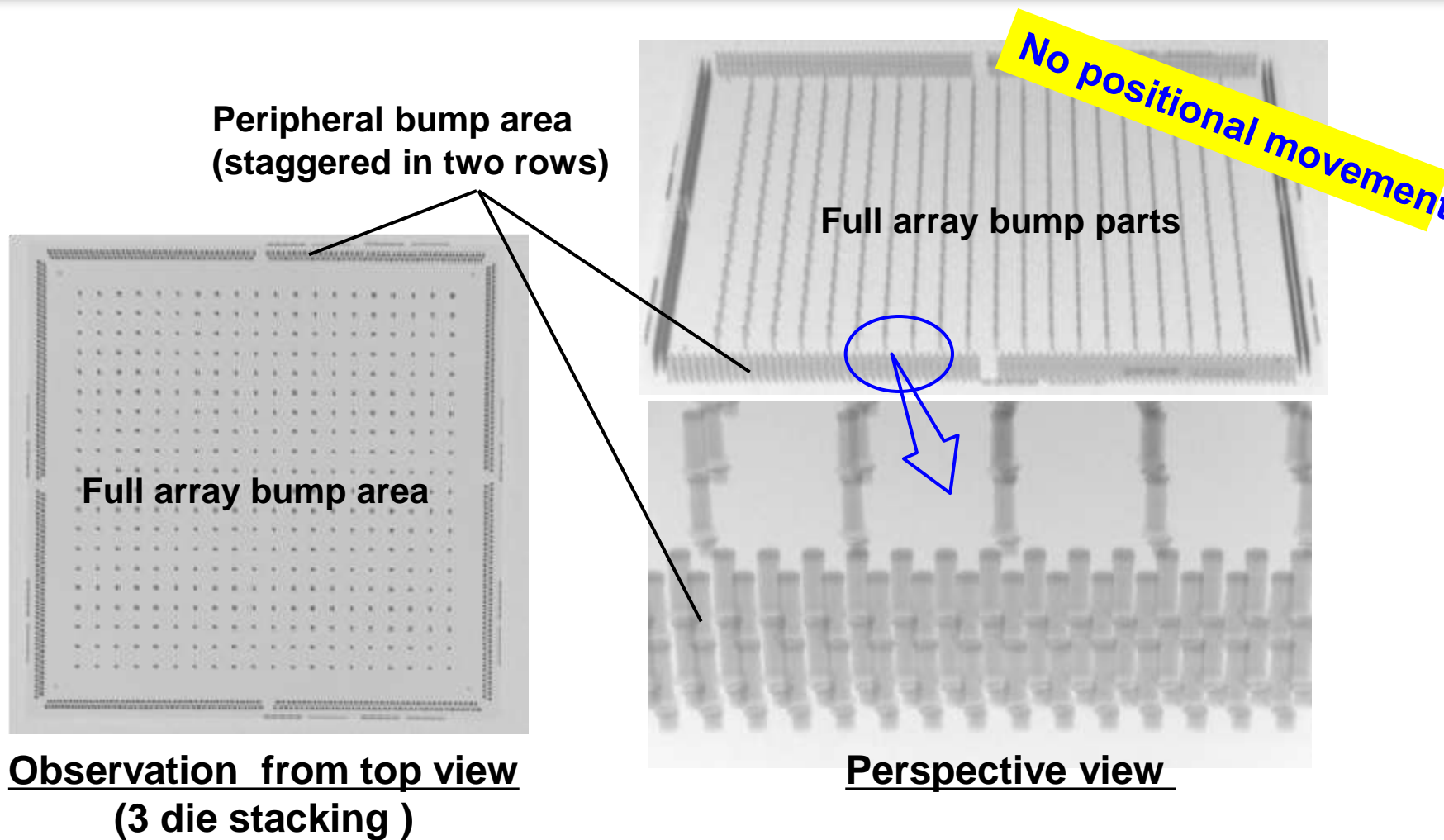
3D die stacking TSV-PKG assembly by Molded reflow process



3 dies stacking CoW

Chip on wafer: $421 \times 3 = 1263$ dies
Gap between dies: 5 mm

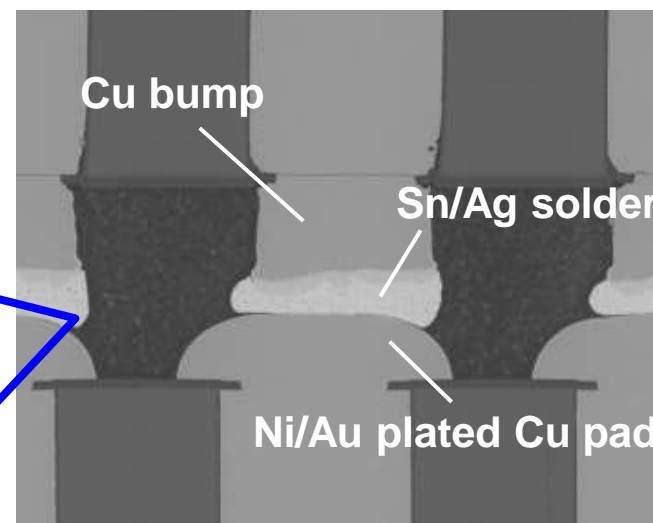
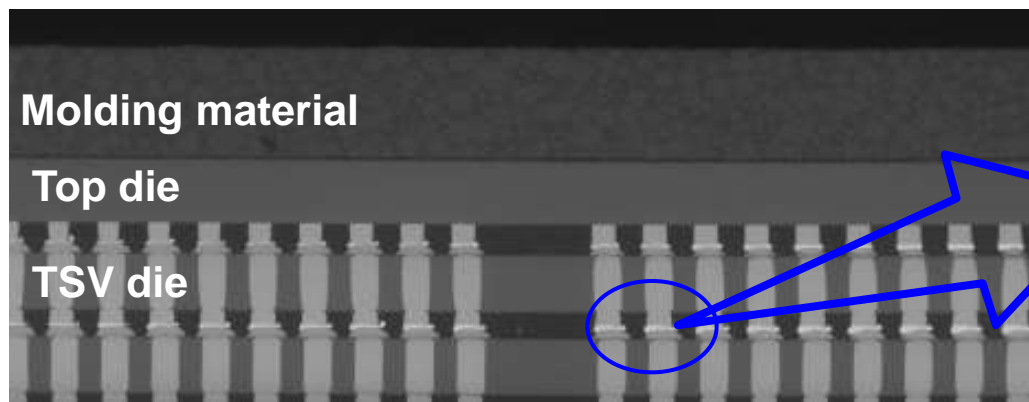
X-ray image after over-molding



No die shift was observed by over-molding.

Cross section of TSV-3D die stacking

Molding cap thickness: 500 μm

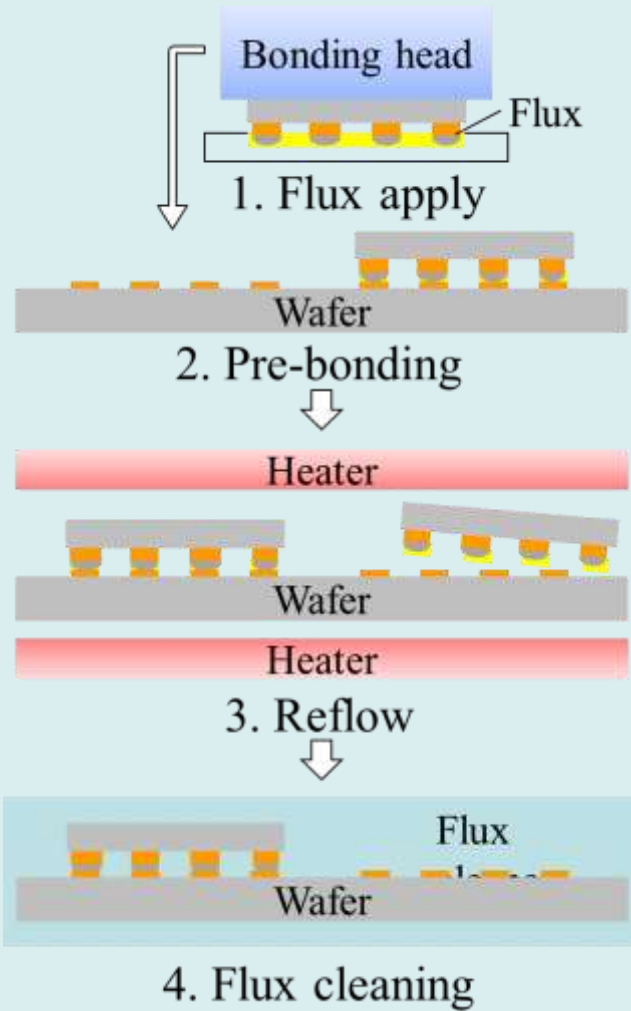


Cross section after reflow

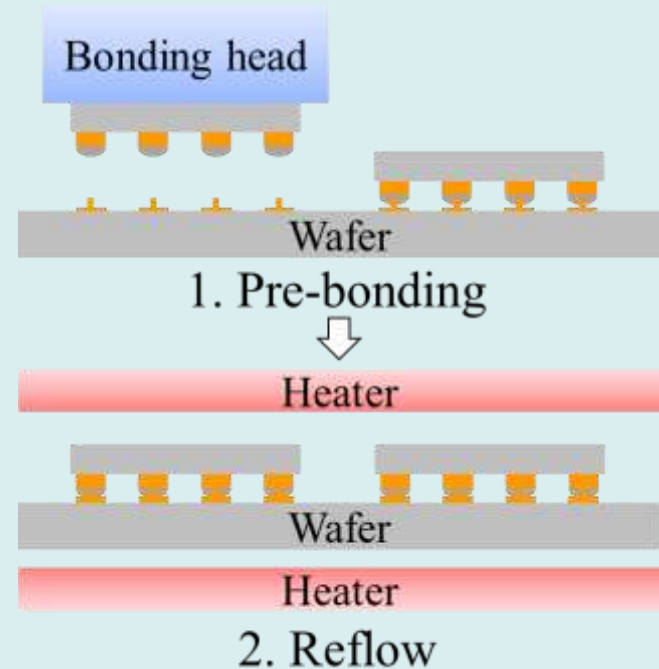
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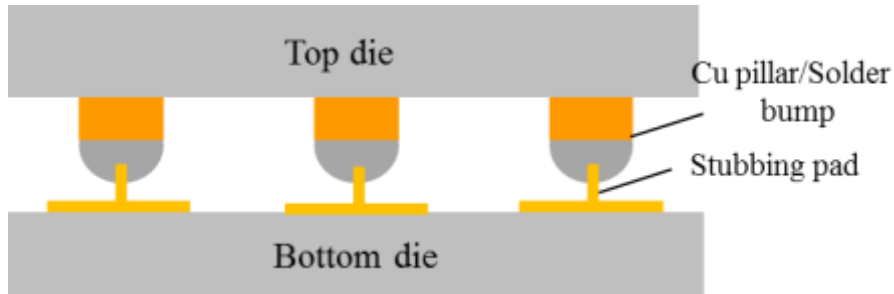
Conventional mass reflow process



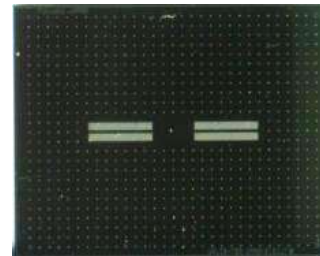
Bump stabbing mass reflow process



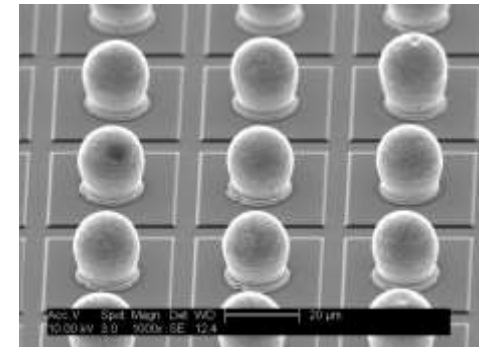
Bump stabbing



Top die



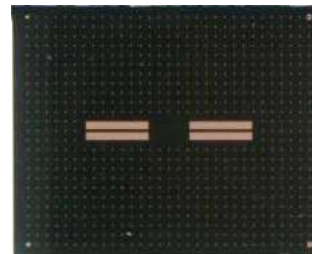
Bumps of the top die



TV die specifications

Top die	Size	10 x 8 mm
	Thickness	0.725 mm
	Bump pitch	I/O : 40 μm Dummy : 300 μm
	Bump size	Φ20 μm
	Bump height	Cu/Sn-Ag : 10 μm/8 μm
Bottom die	Size	10 x 8 mm
	Thickness	0.725 mm
	Pad pitch	I/O : 40 μm Dummy : 300 μm
	Pad size	Φ26 μm
	Pad height	Bottom/Stubbing : 2 μm/3 μm

Bottom die

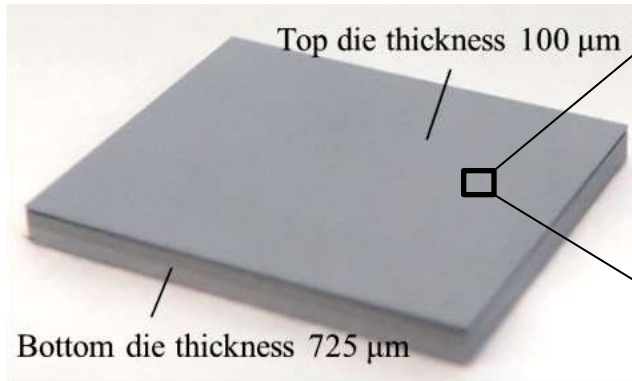


Pads of the bottom die

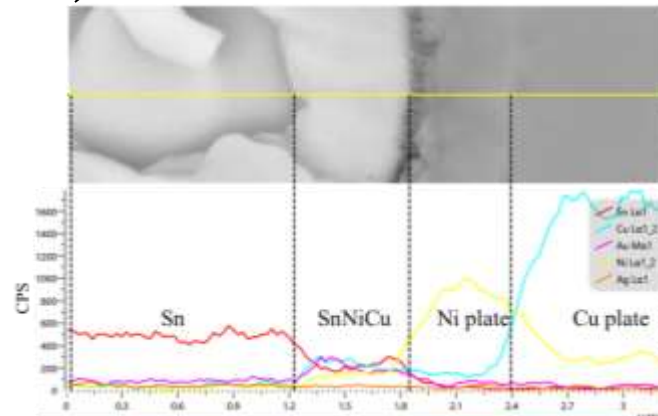
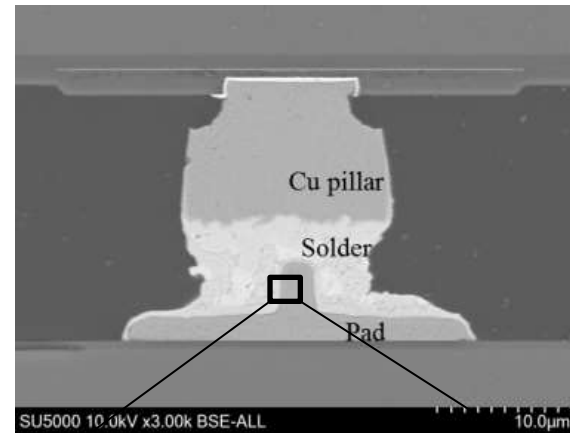


Solder joint by bump stabbing

Stacked dies



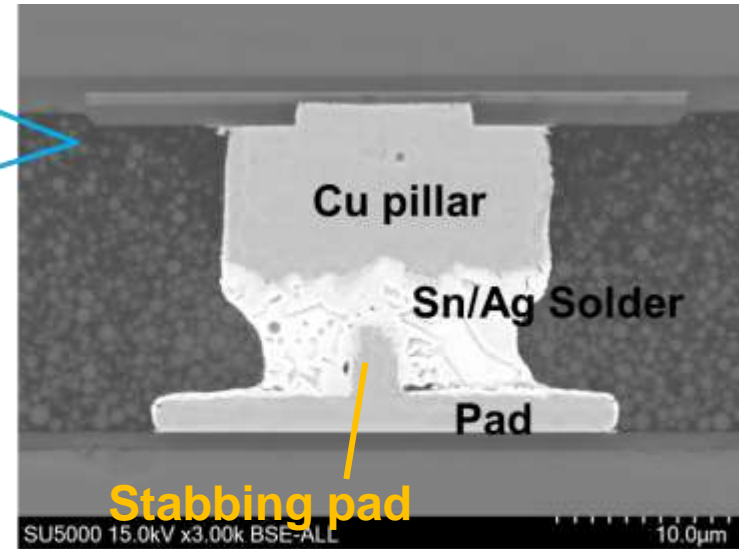
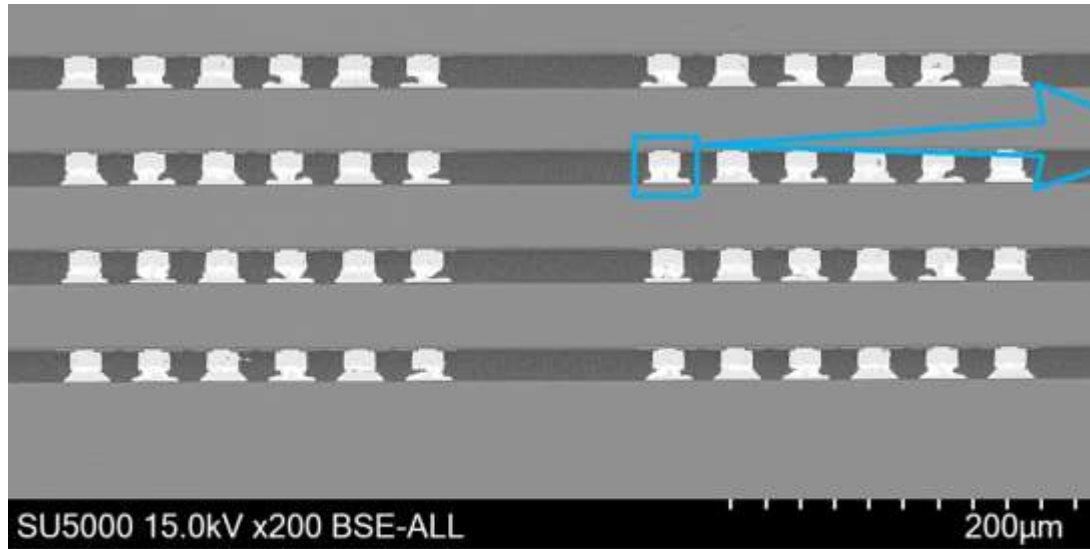
Cross section of joint



Sn-Ni-Cu alloy was formed.

3D die stacking

Die thickness : 40 μm
Stack layer : 4



Cross section after reflow treatment

Solder joints were formed with good alignment

***Details will be presented at session 33-4 (3:30 pm on June 1)**

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Consortium “JOINT” has been founded!

State of the art jisso technologies of material and equipment get together, which can provide the solution.



Enhancement of the productivity of high density interconnection was studied and demonstrated, which were related 2.5D and 3D packages.

- **BFL film : Side by side multiple die TCB gang bonding**
- **Molded reflow: CoW multiple die bonding including 3D die stacking**
- **Bump stabbing process: 3D die stacking**
- **Expanding film**
- **RDL first FO**
- **Consortium “JOINT”**

Thank you!

Hitachi Chemical

Working On Wonders

 **Hitachi Chemical Co., Ltd.**